

EAST - 110-759094 - Walter Jester.wsp.11					
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1	6733	chip same wafer same test			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 11:02 DERWENT; IBM_TDB
2	14218	(clean or cleaning or cleaned) with (probe or needle or pin)			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 11:03 DERWENT; IBM_TDB
3	102	(chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 11:33 DERWENT; IBM_TDB
4	10042	257/48, E21.521, E21.524.ccls. 438/11, 14, 15, 17, 18, FOR101, FOR142.ccls. 716/4-6.ccls.			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 11:29 DERWENT; IBM_TDB
5	13	((chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin))) and (257/48, E21.521, E21.524.ccls. 438/11, 14, 15, 17, 18, FOR101, FOR142.ccls. 716/4-6.ccls.)			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 13:11 DERWENT; IBM_TDB
6	1	(chip same wafer same test) and ((clean or cleaning or cleaned) with (probe or needle or pin)) and database			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 11:33 DERWENT; IBM_TDB
7	29	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48, E21.521, E21.524.ccls. 438/11, 14, 15, 17, 18, FOR101, FOR142.ccls. 716/4-6.ccls.)			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 13:12 DERWENT; IBM_TDB
8	5	((chip same wafer same test) and ((clean or cleaning or cleaned) same (probe or needle or pin))) and (257/48, E21.521, E21.524.ccls. 438/11, 14, 15, 17, 18, FOR101, FOR142.ccls. 716/4-6.ccls.) and database			USPAT; US-PGPUB; 2004/08/27 EPO; JPO; 13:12 DERWENT; IBM_TDB
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